Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	r
10/695,375	BEZRUKOV ET AL.	
Examiner	Art Unit	
Chau Nguyen	2176	

SEARCHED					
Class	Subclass	Date	Examiner		
715	513	2/2/2006	CN		
715	530	2/2/2006	CN		
707	102	2/2/2006	CN		
707	103R	2/2/2006	CN		
707	103Y	2/2/2006	CN		
707	103Z	2/2/2006	CN		
707	200	2/2/2006	CN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Reports	2/2/2006	CN		
	2/3/2006	CN		
NPL Search on IEEE Database	2/3/2006	CN		
Updated Search on East Reports	8/4/2006	CN		
	8/7/2006	CN		
	8/8/2006	CN		